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Understanding **Embedded - FPGAs (Field Programmable Gate Array)**

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	37325
Number of Logic Elements/Cells	477760
Total RAM Bits	35205120
Number of I/O	400
Number of Gates	-
Voltage - Supply	0.97V ~ 1.03V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1156-BBGA, FCBGA
Supplier Device Package	1156-FCBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc7k480t-2ffg1156c

Table 2: Recommended Operating Conditions ⁽¹⁾ (Cont'd)

Symbol	Description	Min	Typ	Max	Units
V _{MGTAVTTRCAL} ⁽⁸⁾	Analog supply voltage for the resistor calibration circuit of the GTX transceiver column	1.17	1.2	1.23	V
XADC					
V _{CCADC}	XADC supply relative to GNDADC	1.71	1.80	1.89	V
V _{REFP}	Externally supplied reference voltage	1.20	1.25	1.30	V
Temperature					
T _j	Junction temperature operating range for commercial (C) temperature devices	0	–	85	°C
	Junction temperature operating range for extended (E) temperature devices	0	–	100	°C
	Junction temperature operating range for industrial (I) temperature devices	–40	–	100	°C

Notes:

1. All voltages are relative to ground.
2. V_{CCINT} and V_{CCBRAM} should be connected to the same supply.
3. Configuration data is retained even if V_{CCO} drops to 0V.
4. Includes V_{CCO} of 1.2V, 1.5V, 1.8V, 2.5V, and 3.3V.
5. The lower absolute voltage specification always applies.
6. A total of 200 mA per bank should not be exceeded.
7. V_{CCBATT} is required only when using bitstream encryption. If battery is not used, connect V_{CCBATT} to either ground or V_{CCAUX}.
8. Each voltage listed requires the filter circuit described in [UG476: 7 Series FPGAs GTX/GTH Transceiver User Guide](#).
9. For data rates ≤ 10.3125 Gb/s, V_{MGTAVCC} should be 1.0V ±3% for lower power consumption.
10. For lower power consumption, V_{MGTAVCC} should be 1.0V ±3% over the entire CPLL frequency range.

Table 3: DC Characteristics Over Recommended Operating Conditions

Symbol	Description	Min	Typ ⁽¹⁾	Max	Units
V _{DRINT}	Data retention V _{CCINT} voltage (below which configuration data might be lost)	0.75	–	–	V
V _{DRI}	Data retention V _{CCAUX} voltage (below which configuration data might be lost)	1.5	–	–	V
I _{REF}	V _{REF} leakage current per pin	–	–	15	μA
I _L	Input or output leakage current per pin (sample-tested)	–	–	15	μA
C _{IN} ⁽²⁾	Die input capacitance at the pad	–	–	8	pF
I _{RPU}	Pad pull-up (when selected) @ V _{IN} = 0V, V _{CCO} = 3.3V	90	–	330	μA
	Pad pull-up (when selected) @ V _{IN} = 0V, V _{CCO} = 2.5V	68	–	250	μA
	Pad pull-up (when selected) @ V _{IN} = 0V, V _{CCO} = 1.8V	34	–	220	μA
	Pad pull-up (when selected) @ V _{IN} = 0V, V _{CCO} = 1.5V	23	–	150	μA
	Pad pull-up (when selected) @ V _{IN} = 0V, V _{CCO} = 1.2V	12	–	120	μA
I _{RPD}	Pad pull-down (when selected) @ V _{IN} = 3.3V	68	–	330	μA
	Pad pull-down (when selected) @ V _{IN} = 1.8V	45	–	180	μA
I _{CCADC}	Analog supply current, analog circuits in powered up state	–	–	25	mA
I _{BATT} ⁽³⁾	Battery supply current	–	–	150	nA

Table 5: Maximum Allowed AC Voltage Overshoot and Undershoot for 1.8V HP I/O Banks⁽¹⁾⁽²⁾ (Cont'd)

AC Voltage Overshoot	% of UI @-40°C to 100°C	AC Voltage Undershoot	% of UI @-40°C to 100°C
V _{CCO} + 0.80	9.71	-0.80	50.0
V _{CCO} + 0.85	4.51	-0.85	28.4
V _{CCO} + 0.90	2.12	-0.90	12.7
V _{CCO} + 0.95	1.01	-0.95	5.79

Notes:

1. A total of 200 mA per bank should not be exceeded.
2. For UI smaller than 20 μs.

Table 6: Typical Quiescent Supply Current

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
I _{CCINTQ}	Quiescent V _{CCINT} supply current	XC7K70T	241	241	241	187	mA
		XC7K160T	474	474	474	368	mA
		XC7K325T	810	810	810	629	mA
		XC7K355T	993	993	993	771	mA
		XC7K410T	1080	1080	1080	838	mA
		XC7K420T	1313	1313	1313	1019	mA
		XC7K480T	1313	1313	1313	1019	mA
I _{CCOQ}	Quiescent V _{CCO} supply current	XC7K70T	1	1	1	1	mA
		XC7K160T	1	1	1	1	mA
		XC7K325T	1	1	1	1	mA
		XC7K355T	1	1	1	1	mA
		XC7K410T	1	1	1	1	mA
		XC7K420T	1	1	1	1	mA
		XC7K480T	1	1	1	1	mA
I _{CCAUXQ}	Quiescent V _{CCAUX} supply current	XC7K70T	21	21	21	21	mA
		XC7K160T	40	40	40	40	mA
		XC7K325T	68	68	68	68	mA
		XC7K355T	75	75	75	75	mA
		XC7K410T	85	85	85	85	mA
		XC7K420T	99	99	99	99	mA
		XC7K480T	99	99	99	99	mA
I _{CCAUX_IOQ}	Quiescent V _{CCAUX_IO} supply current	XC7K70T	N/A	N/A	N/A	N/A	mA
		XC7K160T	2	2	2	2	mA
		XC7K325T	2	2	2	2	mA
		XC7K355T	N/A	N/A	N/A	N/A	mA
		XC7K410T	2	2	2	2	mA
		XC7K420T	N/A	N/A	N/A	N/A	mA
		XC7K480T	N/A	N/A	N/A	N/A	mA

Table 10: Differential SelectIO DC Input and Output Levels

I/O Standard	$V_{ICM}^{(1)}$			$V_{ID}^{(2)}$			$V_{OCM}^{(3)}$			$V_{OD}^{(4)}$		
	V, Min	V, Typ	V, Max	V, Min	V, Typ	V, Max	V, Min	V, Typ	V, Max	V, Min	V, Typ	V, Max
BLVDS_25	0.300	1.200	1.425	0.100	–	–	–	1.250	–	Note 5		
MINI_LVDS_25	0.300	1.200	V_{CCAUX}	0.200	0.400	0.600	1.000	1.200	1.400	0.300	0.450	0.600
PPDS_25	0.200	0.900	V_{CCAUX}	0.100	0.250	0.400	0.500	0.950	1.400	0.100	0.250	0.400
RSDS_25	0.300	0.900	1.500	0.100	0.350	0.600	1.000	1.200	1.400	0.100	0.350	0.600
TMDS_33	2.700	2.965	3.230	0.150	0.675	1.200	$V_{CCO}-0.405$	$V_{CCO}-0.300$	$V_{CCO}-0.190$	0.400	0.600	0.800

Notes:

- V_{ICM} is the input common mode voltage.
- V_{ID} is the input differential voltage ($Q - \bar{Q}$).
- V_{OCM} is the output common mode voltage.
- V_{OD} is the output differential voltage ($Q - \bar{Q}$).
- V_{OD} for BLVDS will vary significantly depending on topology and loading.
- LVDS_25 is specified in Table 12.
- LVDS is specified in Table 13.

Table 11: Complementary Differential SelectIO DC Input and Output Levels

I/O Standard	$V_{ICM}^{(1)}$			$V_{ID}^{(2)}$		$V_{OL}^{(3)}$	$V_{OH}^{(4)}$	I_{OL}	I_{OH}
	V, Min	V, Typ	V, Max	V, Min	V, Max	V, Max	V, Min	mA, Max	mA, Min
DIFF_HSTL_I	0.300	0.750	1.125	0.100	–	0.400	$V_{CCO}-0.400$	8.00	–8.00
DIFF_HSTL_I_18	0.300	0.900	1.425	0.100	–	0.400	$V_{CCO}-0.400$	8.00	–8.00
DIFF_HSTL_II	0.300	0.750	1.125	0.100	–	0.400	$V_{CCO}-0.400$	16.00	–16.00
DIFF_HSTL_II_18	0.300	0.900	1.425	0.100	–	0.400	$V_{CCO}-0.400$	16.00	–16.00
DIFF_HSUL_12	0.300	0.600	0.850	0.100	–	20% V_{CCO}	80% V_{CCO}	0.100	–0.100
DIFF_MOBILE_DDR	0.300	0.900	1.425	0.100	–	10% V_{CCO}	90% V_{CCO}	0.100	–0.100
DIFF_SSTL12	0.300	0.600	0.850	0.100	–	$(V_{CCO}/2) - 0.150$	$(V_{CCO}/2) + 0.150$	14.25	–14.25
DIFF_SSTL135	0.300	0.675	1.000	0.100	–	$(V_{CCO}/2) - 0.150$	$(V_{CCO}/2) + 0.150$	13.0	–13.0
DIFF_SSTL135_R	0.300	0.675	1.000	0.100	–	$(V_{CCO}/2) - 0.150$	$(V_{CCO}/2) + 0.150$	8.9	–8.9
DIFF_SSTL15	0.300	0.750	1.125	0.100	–	$(V_{CCO}/2) - 0.175$	$(V_{CCO}/2) + 0.175$	13.0	–13.0
DIFF_SSTL15_R	0.300	0.750	1.125	0.100	–	$(V_{CCO}/2) - 0.175$	$(V_{CCO}/2) + 0.175$	8.9	–8.9
DIFF_SSTL18_I	0.300	0.900	1.425	0.100	–	$(V_{CCO}/2) - 0.470$	$(V_{CCO}/2) + 0.470$	8.00	–8.00
DIFF_SSTL18_II	0.300	0.900	1.425	0.100	–	$(V_{CCO}/2) - 0.600$	$(V_{CCO}/2) + 0.600$	13.4	–13.4

Notes:

- V_{ICM} is the input common mode voltage.
- V_{ID} is the input differential voltage ($Q - \bar{Q}$).
- V_{OL} is the single-ended low-output voltage.
- V_{OH} is the single-ended high-output voltage.

Table 17: Maximum Physical Interface (PHY) Rate for Memory Interfaces (FFG Packages)⁽¹⁾⁽²⁾

Memory Standard	I/O Bank Type	V _{CCAUX_IO}	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
4:1 Memory Controllers							
DDR3	HP	2.0V	1866	1866	1600	1333	Mb/s
	HP	1.8V	1600	1333	1066	1066	Mb/s
	HR	N/A	1066	1066	800	800	Mb/s
DDR3L	HP	2.0V	1600	1600	1333	1066	Mb/s
	HP	1.8V	1333	1066	800	800	Mb/s
	HR	N/A	800	800	667	667	Mb/s
DDR2	HP	2.0V	800	800	800	800	Mb/s
	HP	1.8V	800	800	800	800	Mb/s
	HR	N/A	800	800	800	800	Mb/s
RLDRAM III ⁽³⁾	HP	2.0V	800	667	667	533	MHz
	HP	1.8V	550	500	450	450	MHz
	HR	N/A	N/A				
2:1 Memory Controllers							
DDR3	HP	2.0V	1066	1066	800	800	Mb/s
	HP	1.8V	1066	1066	800	800	Mb/s
	HR	N/A	1066	1066	800	800	Mb/s
DDR3L	HP	2.0V	1066	1066	800	800	Mb/s
	HP	1.8V	1066	1066	800	800	Mb/s
	HR	N/A	800	800	667	667	Mb/s
DDR2	HP	2.0V	800	800	800	800	Mb/s
	HP	1.8V					
	HR	N/A					
QDR II+ ⁽⁴⁾	HP	2.0V	550	500	450	450	MHz
	HP	1.8V					
	HR	N/A					
RLDRAM II	HP	2.0V	533	500	450	450	MHz
	HP	1.8V					
	HR	N/A					
LPDDR2 ⁽³⁾	HP	2.0V	800	800	800	800	Mb/s
	HP	1.8V	800	800	800	800	Mb/s
	HR	N/A	800	667	667	667	Mb/s

Notes:

1. V_{REF} tracking is required. For more information, see [UG586](#), 7 Series FPGAs Memory Interface Solutions User Guide.
2. When using the internal V_{REF} the maximum data rate is 800 Mb/s (400 MHz).
3. RLDRAM III (BL = 4, BL = 8) and LPDDR2 specifications have not been validated with memory IP.
4. The maximum QDRII+ performance specifications are for burst-length 4 (BL = 4) implementations. Burst length 2 (BL = 2) implementations are limited to 333 MHz for all speed grades and I/O bank types.

Table 20: 1.8V IOB High Performance (HP) Switching Characteristics

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	1.0V		0.9V		1.0V		0.9V		1.0V		0.9V		
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	
LVDS	0.75	0.79	0.92	0.89	1.05	1.17	1.24	1.43	1.68	1.92	2.06	2.04	ns
HSUL_12	0.69	0.72	0.82	0.95	1.65	1.84	2.05	1.80	2.29	2.59	2.87	2.41	ns
DIFF_HSUL_12	0.69	0.72	0.82	0.92	1.65	1.84	2.05	1.47	2.29	2.59	2.87	2.08	ns
HSTL_I_S	0.68	0.72	0.82	0.84	1.15	1.28	1.38	1.46	1.79	2.03	2.20	2.07	ns
HSTL_II_S	0.68	0.72	0.82	0.84	1.05	1.17	1.26	1.44	1.69	1.93	2.08	2.05	ns
HSTL_I_18_S	0.70	0.72	0.82	0.86	1.12	1.24	1.34	1.41	1.75	2.00	2.16	2.02	ns
HSTL_II_18_S	0.70	0.72	0.82	0.86	1.06	1.18	1.26	1.44	1.70	1.94	2.08	2.05	ns
HSTL_I_12_S	0.68	0.72	0.82	0.94	1.14	1.27	1.37	1.43	1.78	2.02	2.20	2.04	ns
HSTL_I_DCI_S	0.68	0.72	0.82	0.78	1.11	1.23	1.33	1.36	1.74	1.99	2.15	1.98	ns
HSTL_II_DCI_S	0.68	0.72	0.82	0.78	1.05	1.17	1.26	1.33	1.69	1.93	2.08	1.94	ns
HSTL_II_T_DCI_S	0.70	0.72	0.82	0.76	1.15	1.28	1.38	1.40	1.78	2.03	2.20	2.01	ns
HSTL_I_DCI_18_S	0.70	0.72	0.82	0.76	1.11	1.23	1.33	1.36	1.74	1.99	2.15	1.98	ns
HSTL_II_DCI_18_S	0.70	0.72	0.82	0.76	1.05	1.16	1.24	1.32	1.69	1.92	2.06	1.93	ns
HSTL_II_T_DCI_18_S	0.70	0.72	0.82	0.76	1.11	1.23	1.33	1.36	1.74	1.99	2.15	1.98	ns
DIFF_HSTL_I_S	0.75	0.79	0.92	0.89	1.15	1.28	1.38	1.47	1.79	2.03	2.20	2.08	ns
DIFF_HSTL_II_S	0.75	0.79	0.92	0.89	1.05	1.17	1.26	1.47	1.69	1.93	2.08	2.08	ns
DIFF_HSTL_I_DCI_S	0.75	0.79	0.92	0.76	1.15	1.28	1.38	1.47	1.78	2.03	2.20	2.08	ns
DIFF_HSTL_II_DCI_S	0.75	0.79	0.92	0.76	1.05	1.17	1.26	1.40	1.69	1.93	2.08	2.01	ns
DIFF_HSTL_I_18_S	0.75	0.79	0.92	0.89	1.12	1.24	1.34	1.46	1.75	2.00	2.16	2.07	ns
DIFF_HSTL_II_18_S	0.75	0.79	0.92	0.89	1.06	1.18	1.26	1.47	1.70	1.94	2.08	2.08	ns
DIFF_HSTL_I_DCI_18_S	0.75	0.79	0.92	0.75	1.11	1.23	1.33	1.46	1.74	1.99	2.15	2.07	ns
DIFF_HSTL_II_DCI_18_S	0.75	0.79	0.92	0.75	1.05	1.16	1.24	1.41	1.69	1.92	2.06	2.02	ns
DIFF_HSTL_II_T_DCI_18_S	0.75	0.79	0.92	0.76	1.11	1.23	1.33	1.46	1.74	1.99	2.15	2.07	ns
HSTL_I_F	0.68	0.72	0.82	0.84	1.02	1.14	1.22	1.26	1.66	1.90	2.04	1.87	ns
HSTL_II_F	0.68	0.72	0.82	0.84	0.97	1.08	1.15	1.29	1.61	1.84	1.97	1.90	ns
HSTL_I_18_F	0.70	0.72	0.82	0.86	1.04	1.16	1.24	1.32	1.68	1.91	2.06	1.93	ns
HSTL_II_18_F	0.70	0.72	0.82	0.86	0.98	1.09	1.16	1.35	1.62	1.85	1.98	1.96	ns
HSTL_I_12_F	0.68	0.72	0.82	0.94	1.02	1.13	1.21	1.26	1.65	1.88	2.03	1.87	ns
HSTL_I_DCI_F	0.68	0.72	0.82	0.78	1.04	1.16	1.24	1.30	1.67	1.91	2.06	1.91	ns
HSTL_II_DCI_F	0.68	0.72	0.82	0.78	0.97	1.08	1.15	1.22	1.61	1.84	1.97	1.83	ns
HSTL_II_T_DCI_F	0.70	0.72	0.82	0.76	1.02	1.14	1.22	1.26	1.66	1.90	2.04	1.87	ns
HSTL_I_DCI_18_F	0.70	0.72	0.82	0.76	1.04	1.16	1.24	1.30	1.67	1.91	2.06	1.91	ns
HSTL_II_DCI_18_F	0.70	0.72	0.82	0.76	0.98	1.09	1.16	1.27	1.61	1.85	1.98	1.88	ns
HSTL_II_T_DCI_18_F	0.70	0.72	0.82	0.76	1.04	1.16	1.24	1.30	1.67	1.91	2.06	1.91	ns
DIFF_HSTL_I_F	0.75	0.79	0.92	0.89	1.02	1.14	1.22	1.35	1.66	1.90	2.04	1.96	ns
DIFF_HSTL_II_F	0.75	0.79	0.92	0.89	0.97	1.08	1.15	1.35	1.61	1.84	1.97	1.96	ns
DIFF_HSTL_I_DCI_F	0.75	0.79	0.92	0.76	1.02	1.14	1.22	1.35	1.66	1.90	2.04	1.96	ns

Table 21 specifies the values of T_{IOTPHZ} and $T_{IOIBUFDISABLE}$. T_{IOTPHZ} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is enabled (i.e., a high impedance state). $T_{IOIBUFDISABLE}$ is described as the IOB delay from IBUFDISABLE to O output. In HP I/O banks, the internal DCI termination turn-off time is always faster than T_{IOTPHZ} when the DCITERMDISABLE pin is used. In HR I/O banks, the internal IN_TERM termination turn-off time is always faster than T_{IOTPHZ} when the INTERMDISABLE pin is used.

Table 21: IOB 3-state Output Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
T_{IOTPHZ}	T input to pad high-impedance	0.76	0.86	0.99	0.62	ns
$T_{IOIBUFDISABLE_HR}$	IBUF turn-on time from IBUFDISABLE to O output for HR I/O banks	1.72	1.89	2.14	2.17	ns
$T_{IOIBUFDISABLE_HP}$	IBUF turn-on time from IBUFDISABLE to O output for HP I/O banks	1.31	1.46	1.76	1.86	ns

Table 23: OLOGIC Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
Setup/Hold						
T_{ODCK}/T_{OCKD}	D1/D2 pins Setup/Hold with respect to CLK	0.45/-0.13	0.50/-0.13	0.58/-0.13	0.79/-0.18	ns
T_{OOCECK}/T_{OCKOCE}	OCE pin Setup/Hold with respect to CLK	0.28/0.03	0.29/0.03	0.45/0.03	0.35/-0.10	ns
T_{OSRCK}/T_{OCKSR}	SR pin Setup/Hold with respect to CLK	0.32/0.18	0.38/0.18	0.70/0.18	0.62/-0.04	ns
T_{OTCK}/T_{OCKT}	T1/T2 pins Setup/Hold with respect to CLK	0.49/-0.16	0.56/-0.16	0.68/-0.16	0.67/-0.18	ns
T_{OTCECK}/T_{OCKTCE}	TCE pin Setup/Hold with respect to CLK	0.28/0.01	0.30/0.01	0.45/0.01	0.31/-0.10	ns
Combinatorial						
T_{ODQ}	D1 to OQ out or T1 to TQ out	0.73	0.81	0.97	1.18	ns
Sequential Delays						
T_{OCKQ}	CLK to OQ/TQ out	0.41	0.43	0.49	0.63	ns
$T_{RQ_OLOGICE2}$	SR pin to OQ/TQ out (HP I/O banks only)	0.63	0.70	0.83	1.12	ns
$T_{GSRQ_OLOGICE2}$	Global Set/Reset to Q outputs (HP I/O banks only)	7.60	7.60	10.51	11.39	ns
$T_{RQ_OLOGICE3}$	SR pin to OQ/TQ out (HR I/O banks only)	0.63	0.70	0.83	1.12	ns
$T_{GSRQ_OLOGICE3}$	Global Set/Reset to Q outputs (HR I/O banks only)	7.60	7.60	10.51	11.39	ns
Set/Reset						
$T_{RPW_OLOGICE2}$	Minimum Pulse Width, SR inputs (HP I/O banks only)	0.54	0.54	0.63	0.68	ns, Min
$T_{RPW_OLOGICE3}$	Minimum Pulse Width, SR inputs (HR I/O banks only)	0.54	0.54	0.63	0.68	ns, Min

Input/Output Delay Switching Characteristics

Table 26: Input/Output Delay Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
IDELAYCTRL						
T _{DLYCCO_RDY}	Reset to Ready for IDELAYCTRL	3.22	3.22	3.22	3.22	µs
F _{IDELAYCTRL_REF}	Attribute REFCLK frequency = 200.00 ⁽¹⁾	200.00	200.00	200.00	200.00	MHz
	Attribute REFCLK frequency = 300.00 ⁽¹⁾	300.00	300.00	N/A	N/A	MHz
IDELAYCTRL_REF_PRECISION	REFCLK precision	±10	±10	±10	±10	MHz
T _{IDELAYCTRL_RPW}	Minimum Reset pulse width	52.00	52.00	52.00	52.00	ns
IDELAY/ODELAY						
T _{IDELAYRESOLUTION}	IDELAY/ODELAY chain delay resolution	1/(32 x 2 x F _{REF})				ps
T _{IDELAYPAT_JIT} and T _{ODELAYPAT_JIT}	Pattern dependent period jitter in delay chain for clock pattern. ⁽²⁾	0	0	0	0	ps per tap
	Pattern dependent period jitter in delay chain for random data pattern (PRBS 23) ⁽³⁾	±5	±5	±5	±5	ps per tap
	Pattern dependent period jitter in delay chain for random data pattern (PRBS 23) ⁽⁴⁾	±9	±9	±9	±9	ps per tap
T _{IDELAY_CLK_MAX} / T _{ODELAY_CLK_MAX}	Maximum frequency of CLK input to IDELAY/ODELAY	800.00	800.00	710.00	710.00	MHz
T _{IDCCK_CE} / T _{IDCKC_CE}	CE pin Setup/Hold with respect to C for IDELAY	0.11/0.10	0.14/0.12	0.18/0.14	0.14/0.16	ns
T _{ODCCK_CE} / T _{ODCKC_CE}	CE pin Setup/Hold with respect to C for ODELAY	0.14/0.03	0.16/0.04	0.19/0.05	0.28/0.06	ns
T _{IDCCK_INC} / T _{IDCKC_INC}	INC pin Setup/Hold with respect to C for IDELAY	0.10/0.14	0.12/0.16	0.14/0.20	0.10/0.23	ns
T _{ODCCK_INC} / T _{ODCKC_INC}	INC pin Setup/Hold with respect to C for ODELAY	0.10/0.07	0.12/0.08	0.13/0.09	0.19/0.16	ns
T _{IDCCK_RST} / T _{IDCKC_RST}	RST pin Setup/Hold with respect to C for IDELAY	0.13/0.08	0.14/0.10	0.16/0.12	0.22/0.19	ns
T _{ODCCK_RST} / T _{ODCKC_RST}	RST pin Setup/Hold with respect to C for ODELAY	0.16/0.04	0.19/0.06	0.24/0.08	0.32/0.11	ns
T _{IDDO_IDATAIN}	Propagation delay through IDELAY	Note 5	Note 5	Note 5	Note 5	ps
T _{ODDO_ODATAIN}	Propagation delay through ODELAY	Note 5	Note 5	Note 5	Note 5	ps

Notes:

1. Average Tap Delay at 200 MHz = 78 ps, at 300 MHz = 52 ps.
2. When HIGH_PERFORMANCE mode is set to TRUE or FALSE.
3. When HIGH_PERFORMANCE mode is set to TRUE.
4. When HIGH_PERFORMANCE mode is set to FALSE.
5. Delay depends on IDELAY/ODELAY tap setting. See TRACE report for actual values.

CLB Switching Characteristics

Table 28: CLB Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Combinatorial Delays						
T_{ILO}	An – Dn LUT address to A	0.05	0.05	0.06	0.07	ns, Max
T_{ILO_2}	An – Dn LUT address to AMUX/CMUX	0.15	0.16	0.19	0.22	ns, Max
T_{ILO_3}	An – Dn LUT address to BMUX_A	0.24	0.25	0.30	0.37	ns, Max
T_{ITO}	An – Dn inputs to A – D Q outputs	0.58	0.61	0.74	0.91	ns, Max
T_{AXA}	AX inputs to AMUX output	0.38	0.40	0.49	0.62	ns, Max
T_{AXB}	AX inputs to BMUX output	0.40	0.42	0.52	0.66	ns, Max
T_{AXC}	AX inputs to CMUX output	0.39	0.41	0.50	0.62	ns, Max
T_{AXD}	AX inputs to DMUX output	0.43	0.44	0.52	0.67	ns, Max
T_{BxB}	BX inputs to BMUX output	0.31	0.33	0.40	0.51	ns, Max
T_{BxD}	BX inputs to DMUX output	0.38	0.39	0.47	0.62	ns, Max
T_{CxC}	CX inputs to CMUX output	0.27	0.28	0.34	0.43	ns, Max
T_{CxD}	CX inputs to DMUX output	0.33	0.34	0.41	0.54	ns, Max
T_{DxD}	DX inputs to DMUX output	0.32	0.33	0.40	0.52	ns, Max
Sequential Delays						
T_{CKO}	Clock to AQ – DQ outputs	0.26	0.27	0.32	0.40	ns, Max
T_{SHCKO}	Clock to AMUX – DMUX outputs	0.32	0.32	0.39	0.46	ns, Max
Setup and Hold Times of CLB Flip-Flops Before/After Clock CLK						
T_{AS}/T_{AH}	$A_N – D_N$ input to CLK on A – D Flip Flops	0.01/0.12	0.02/0.13	0.03/0.18	0.02/0.18	ns, Min
T_{DICK}/T_{CKDI}	$A_X – D_X$ input to CLK on A – D Flip Flops	0.04/0.14	0.04/0.14	0.05/0.20	0.05/0.21	ns, Min
	$A_X – D_X$ input through MUXs and/or carry logic to CLK on A – D Flip Flops	0.36/0.10	0.37/0.11	0.46/0.16	0.56/0.15	ns, Min
$T_{CECK_CLB}/T_{CKCE_CLB}$	CE input to CLK on A – D Flip Flops	0.19/0.05	0.20/0.05	0.25/0.05	0.24/0.04	ns, Min
T_{SRCK}/T_{CKSR}	SR input to CLK on A – D Flip Flops	0.30/0.05	0.31/0.07	0.37/0.09	0.48/0.05	ns, Min
Set/Reset						
T_{SRMIN}	SR input minimum pulse width	0.52	0.78	1.04	0.95	ns, Min
T_{RQ}	Delay from SR input to AQ – DQ flip-flops	0.38	0.38	0.46	0.59	ns, Max
T_{CEO}	Delay from CE input to AQ – DQ flip-flops	0.34	0.35	0.43	0.54	ns, Max
F_{TOG}	Toggle frequency (for export control)	1818	1818	1818	1286	MHz

Block RAM and FIFO Switching Characteristics

Table 31: Block RAM and FIFO Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Block RAM and FIFO Clock-to-Out Delays						
T _{RCKO_DO} and T _{RCKO_DO_REG} ⁽¹⁾	Clock CLK to DOUT output (without output register) ⁽²⁾⁽³⁾	1.57	1.80	2.08	2.44	ns, Max
	Clock CLK to DOUT output (with output register) ⁽⁴⁾⁽⁵⁾	0.54	0.63	0.75	0.86	ns, Max
T _{RCKO_DO_ECC} and T _{RCKO_DO_ECC_REG}	Clock CLK to DOUT output with ECC (without output register) ⁽²⁾⁽³⁾	2.35	2.58	3.26	4.49	ns, Max
	Clock CLK to DOUT output with ECC (with output register) ⁽⁴⁾⁽⁵⁾	0.62	0.69	0.80	0.94	ns, Max
T _{RCKO_DO_CASCOUT} and T _{RCKO_DO_CASCOUT_REG}	Clock CLK to DOUT output with Cascade (without output register) ⁽²⁾	2.21	2.45	2.80	3.19	ns, Max
	Clock CLK to DOUT output with Cascade (with output register) ⁽⁴⁾	0.98	1.08	1.24	1.32	ns, Max
T _{RCKO_FLAGS}	Clock CLK to FIFO flags outputs ⁽⁶⁾	0.65	0.74	0.89	0.97	ns, Max
T _{RCKO_POINTERS}	Clock CLK to FIFO pointers outputs ⁽⁷⁾	0.79	0.87	0.98	1.10	ns, Max
T _{RCKO_PARITY_ECC}	Clock CLK to ECCPARITY in ECC encode only mode	0.66	0.72	0.80	0.93	ns, Max
T _{RCKO_SDBIT_ECC} and T _{RCKO_SDBIT_ECC_REG}	Clock CLK to BITERR (without output register)	2.17	2.38	3.01	4.15	ns, Max
	Clock CLK to BITERR (with output register)	0.57	0.65	0.76	0.89	ns, Max
T _{RCKO_RDADDR_ECC} and T _{RCKO_RDADDR_ECC_REG}	Clock CLK to RDADDR output with ECC (without output register)	0.64	0.74	0.90	0.98	ns, Max
	Clock CLK to RDADDR output with ECC (with output register)	0.71	0.79	0.92	1.10	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{RCKC_ADDRA} /T _{RCKC_ADDRA}	ADDR inputs ⁽⁸⁾	0.38/0.27	0.42/0.28	0.48/0.31	0.65/0.38	ns, Min
T _{RDCK_DI_WF_NC} / T _{RCKD_DI_WF_NC}	Data input setup/hold time when block RAM is configured in WRITE_FIRST or NO_CHANGE mode ⁽⁹⁾	0.49/0.51	0.55/0.53	0.63/0.57	0.78/0.64	ns, Min
T _{RDCK_DI_RF} /T _{RCKD_DI_RF}	Data input setup/hold time when block RAM is configured in READ_FIRST mode ⁽⁹⁾	0.17/0.25	0.19/0.29	0.21/0.35	0.25/0.32	ns, Min
T _{RDCK_DI_ECC} / T _{RCKD_DI_ECC}	DIN inputs with block RAM ECC in standard mode ⁽⁹⁾	0.42/0.37	0.47/0.39	0.53/0.43	0.66/0.46	ns, Min
T _{RDCK_DI_ECCW} / T _{RCKD_DI_ECCW}	DIN inputs with block RAM ECC encode only ⁽⁹⁾	0.79/0.37	0.87/0.39	0.99/0.43	1.17/0.41	ns, Min
T _{RDCK_DI_ECC_FIFO} / T _{RCKD_DI_ECC_FIFO}	DIN inputs with FIFO ECC in standard mode ⁽⁹⁾	0.89/0.47	0.98/0.50	1.12/0.54	1.32/0.65	ns, Min
T _{RCKC_INJECTBITERR} / T _{RCKC_INJECTBITERR}	Inject single/double bit error in ECC mode	0.49/0.30	0.55/0.31	0.63/0.34	0.78/0.41	ns, Min
T _{RCKC_EN} /T _{RCKC_EN}	Block RAM Enable (EN) input	0.30/0.17	0.33/0.18	0.38/0.20	0.48/0.22	ns, Min
T _{RCKC_REGCE} /T _{RCKC_REGCE}	CE input of output register	0.21/0.13	0.25/0.13	0.31/0.14	0.34/0.16	ns, Min
T _{RCKC_RSTREG} /T _{RCKC_RSTREG}	Synchronous RSTREG input	0.25/0.06	0.27/0.06	0.29/0.06	0.35/0.06	ns, Min

Table 32: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Setup and Hold Times of the RST Pins						
$T_{\text{DSPDCK}}\{\text{RSTA}; \text{RSTB}\}_{\text{AREG}; \text{BREG}} / T_{\text{DSPCKD}}\{\text{RSTA}; \text{RSTB}\}_{\text{AREG}; \text{BREG}}$	{RSTA, RSTB} input to {A, B} register CLK	0.34/ 0.10	0.39/ 0.11	0.47/ 0.13	0.53/ 0.34	ns
$T_{\text{DSPDCK_RSTC_CREG}} / T_{\text{DSPCKD_RSTC_CREG}}$	RSTC input to C register CLK	0.06/ 0.22	0.07/ 0.24	0.08/ 0.26	0.08/ 0.31	ns
$T_{\text{DSPDCK_RSTD_DREG}} / T_{\text{DSPCKD_RSTD_DREG}}$	RSTD input to D register CLK	0.37/ 0.06	0.42/ 0.06	0.50/ 0.07	0.57/ 0.07	ns
$T_{\text{DSPDCK_RSTM_MREG}} / T_{\text{DSPCKD_RSTM_MREG}}$	RSTM input to M register CLK	0.18/ 0.18	0.20/ 0.21	0.23/ 0.24	0.24/ 0.29	ns
$T_{\text{DSPDCK_RSTP_PREG}} / T_{\text{DSPCKD_RSTP_PREG}}$	RSTP input to P register CLK	0.24/ 0.01	0.26/ 0.01	0.30/ 0.01	0.37/ 0.00	ns
Combinatorial Delays from Input Pins to Output Pins						
$T_{\text{DSPDO_A_CARRYOUT_MULT}}$	A input to CARRYOUT output using multiplier	3.21	3.69	4.39	5.60	ns
$T_{\text{DSPDO_D_P_MULT}}$	D input to P output using multiplier	3.15	3.61	4.30	5.44	ns
$T_{\text{DSPDO_A_P}}$	A input to P output not using multiplier	1.30	1.48	1.76	2.10	ns
$T_{\text{DSPDO_C_P}}$	C input to P output	1.13	1.30	1.55	1.84	ns
Combinatorial Delays from Input Pins to Cascading Output Pins						
$T_{\text{DSPDO}}\{\text{A}; \text{B}\}_{\{\text{ACOUT}; \text{BCOUT}\}}$	{A, B} input to {ACOUT, BCOUT} output	0.47	0.53	0.63	0.75	ns
$T_{\text{DSPDO}}\{\text{A}; \text{B}\}_{\text{CARRYCASCOUT_MULT}}$	{A, B} input to CARRYCASCOUT output using multiplier	3.44	3.94	4.69	5.96	ns
$T_{\text{DSPDO_D_CARRYCASCOUT_MULT}}$	D input to CARRYCASCOUT output using multiplier	3.36	3.85	4.58	5.77	ns
$T_{\text{DSPDO}}\{\text{A}; \text{B}\}_{\text{CARRYCASCOUT}}$	{A, B} input to CARRYCASCOUT output not using multiplier	1.50	1.72	2.04	2.44	ns
$T_{\text{DSPDO_C_CARRYCASCOUT}}$	C input to CARRYCASCOUT output	1.34	1.53	1.83	2.18	ns
Combinatorial Delays from Cascading Input Pins to All Output Pins						
$T_{\text{DSPDO_ACIN_P_MULT}}$	ACIN input to P output using multiplier	3.09	3.55	4.24	5.42	ns
$T_{\text{DSPDO_ACIN_P}}$	ACIN input to P output not using multiplier	1.16	1.33	1.59	2.07	ns
$T_{\text{DSPDO_ACIN_ACOUT}}$	ACIN input to ACOUT output	0.32	0.37	0.45	0.53	ns
$T_{\text{DSPDO_ACIN_CARRYCASCOUT_MULT}}$	ACIN input to CARRYCASCOUT output using multiplier	3.30	3.79	4.52	5.76	ns
$T_{\text{DSPDO_ACIN_CARRYCASCOUT}}$	ACIN input to CARRYCASCOUT output not using multiplier	1.37	1.57	1.87	2.40	ns
$T_{\text{DSPDO_PCIN_P}}$	PCIN input to P output	0.94	1.08	1.29	1.54	ns
$T_{\text{DSPDO_PCIN_CARRYCASCOUT}}$	PCIN input to CARRYCASCOUT output	1.15	1.32	1.57	1.88	ns
Clock to Outs from Output Register Clock to Output Pins						
$T_{\text{DSPCKO_P_PREG}}$	CLK PREG to P output	0.33	0.35	0.39	0.45	ns
$T_{\text{DSPCKO_CARRYCASCOUT_PREG}}$	CLK PREG to CARRYCASCOUT output	0.44	0.50	0.59	0.71	ns

Clock Buffers and Networks

Table 33: Global Clock Switching Characteristics (Including BUFGCTRL)

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
$T_{BCCCK_CE}/T_{BCCCK_CE}^{(1)}$	CE pins Setup/Hold	0.12/0.30	0.14/0.38	0.26/0.38	0.23/0.40	ns
$T_{BCCCK_S}/T_{BCCCK_S}^{(1)}$	S pins Setup/Hold	0.12/0.30	0.14/0.38	0.26/0.38	0.23/0.40	ns
$T_{BCCCKO_O}^{(2)}$	BUFGCTRL delay from I0/I1 to O	0.08	0.10	0.12	0.10	ns
Maximum Frequency						
F_{MAX_BUFG}	Global clock tree (BUFG)	741.00	710.00	625.00	560.00	MHz

Notes:

- T_{BCCCK_CE} and T_{BCCCK_S} must be satisfied to assure glitch-free operation of the global clock when switching between clocks. These parameters do not apply to the BUFGMUX primitive that assures glitch-free operation. The other global clock setup and hold times are optional; only needing to be satisfied if device operation requires simulation matches on a cycle-for-cycle basis when switching between clocks.
- T_{BCCCKO_O} (BUFG delay from I0 to O) values are the same as T_{BCCCKO_O} values.

Table 34: Input/Output Clock Switching Characteristics (BUFIO)

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
T_{BIOCKO_O}	Clock to out delay from I to O	1.04	1.14	1.32	1.48	ns
Maximum Frequency						
F_{MAX_BUFIO}	I/O clock tree (BUFIO)	800.00	800.00	710.00	710.00	MHz

Table 35: Regional Clock Buffer Switching Characteristics (BUFR)

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
T_{BRCKO_O}	Clock to out delay from I to O	0.60	0.65	0.77	1.06	ns
$T_{BRCKO_O_BYP}$	Clock to out delay from I to O with Divide Bypass attribute set	0.30	0.32	0.38	0.57	ns
T_{BRDO_O}	Propagation delay from CLR to O	0.71	0.75	0.96	0.93	ns
Maximum Frequency						
$F_{MAX_BUFR}^{(1)}$	Regional clock tree (BUFR)	600.00	540.00	450.00	450.00	MHz

Notes:

- The maximum input frequency to the BUFR is the BUFIO F_{MAX} frequency.

Table 38: MMCM Specification (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
$T_{MMCMCK_DEN}/T_{MMCMCKD_DEN}$	DEN Setup/Hold	1.76/0.00	1.97/0.00	2.29/0.00	2.40/0.00	ns, Min
$T_{MMCMCK_DWE}/T_{MMCMCKD_DWE}$	DWE Setup/Hold	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
$T_{MMCMCKO_DRDY}$	CLK to out of DRDY	0.65	0.72	0.99	0.70	ns, Max
F_{DCK}	DCLK frequency	200.00	200.00	200.00	100.00	MHz, Max

Notes:

1. The MMCM does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
2. The static offset is measured between any MMCM outputs with identical phase.
3. Values for this parameter are available in the Clocking Wizard.
See http://www.xilinx.com/products/intellectual-property/clocking_wizard.htm.
4. Includes global clock buffer.
5. Calculated as $F_{VCO}/128$ assuming output duty cycle is 50%.
6. When $CLKOUT4_CASCADE = TRUE$, $MMCM_F_{OUTMIN}$ is 0.036 MHz.

PLL Switching Characteristics

Table 39: PLL Specification

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
PLL_F_{INMAX}	Maximum Input Clock Frequency	1066.00	933.00	800.00	800.00	MHz
PLL_F_{INMIN}	Minimum Input Clock Frequency	19.00	19.00	19.00	19.00	MHz
$PLL_F_{INJITTER}$	Maximum Input Clock Period Jitter	< 20% of clock input period or 1 ns Max				
PLL_F_{INDUTY}	Allowable Input Duty Cycle: 19—49 MHz	25.00	25.00	25.00	25.00	%
	Allowable Input Duty Cycle: 50—199 MHz	30.00	30.00	30.00	30.00	%
	Allowable Input Duty Cycle: 200—399 MHz	35.00	35.00	35.00	35.00	%
	Allowable Input Duty Cycle: 400—499 MHz	40.00	40.00	40.00	40.00	%
	Allowable Input Duty Cycle: >500 MHz	45.00	45.00	45.00	45.00	%
PLL_F_{VCOMIN}	Minimum PLL VCO Frequency	800.00	800.00	800.00	800.00	MHz
PLL_F_{VCOMAX}	Maximum PLL VCO Frequency	2133.00	1866.00	1600.00	1600.00	MHz
$PLL_F_{BANDWIDTH}$	Low PLL Bandwidth at Typical ⁽¹⁾	1.00	1.00	1.00	1.00	MHz
	High PLL Bandwidth at Typical ⁽¹⁾	4.00	4.00	4.00	4.00	MHz
$PLL_T_{STATPHAOFFSET}$	Static Phase Offset of the PLL Outputs ⁽²⁾	0.12	0.12	0.12	0.12	ns
$PLL_T_{OUTJITTER}$	PLL Output Jitter	Note 3				
$PLL_T_{OUTDUTY}$	PLL Output Clock Duty Cycle Precision ⁽⁴⁾	0.20	0.20	0.20	0.25	ns
$PLL_T_{LOCKMAX}$	PLL Maximum Lock Time	100	100	100	100	μs
PLL_F_{OUTMAX}	PLL Maximum Output Frequency	1066.00	933.00	800.00	800.00	MHz
PLL_F_{OUTMIN}	PLL Minimum Output Frequency ⁽⁵⁾	6.25	6.25	6.25	6.25	MHz
$PLL_T_{EXTFDVAR}$	External Clock Feedback Variation	< 20% of clock input period or 1 ns Max				
$PLL_RST_{MINPULSE}$	Minimum Reset Pulse Width	5.00	5.00	5.00	5.00	ns

Table 39: PLL Specification (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
PLL_FPFDMAX	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to High or Optimized	550.00	500.00	450.00	450.00	MHz
	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to Low	300.00	300.00	300.00	300.00	MHz
PLL_FPFDMIN	Minimum Frequency at the Phase Frequency Detector	19.00	19.00	19.00	19.00	MHz
PLL_TFBDELAY	Maximum Delay in the Feedback Path	3 ns Max or one CLKIN cycle				
Dynamic Reconfiguration Port (DRP) for PLL Before and After DCLK						
T _{PLLCKC_DADDR} / T _{PLLCKC_DADDR}	Setup and hold of D address	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T _{PLLCKC_DI} / T _{PLLCKC_DI}	Setup and hold of D input	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T _{PLLCKC_DEN} / T _{PLLCKC_DEN}	Setup and hold of D enable	1.76/0.00	1.97/0.00	2.29/0.00	2.40/0.00	ns, Min
T _{PLLCKC_DWE} / T _{PLLCKC_DWE}	Setup and hold of D write enable	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T _{PLLCKO_DRDY}	CLK to out of DRDY	0.65	0.72	0.99	0.70	ns, Max
F _{DCK}	DCLK frequency	200.00	200.00	200.00	100.00	MHz, Max

Notes:

1. The PLL does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
2. The static offset is measured between any PLL outputs with identical phase.
3. Values for this parameter are available in the Clocking Wizard.
See http://www.xilinx.com/products/intellectual-property/clocking_wizard.htm.
4. Includes global clock buffer.
5. Calculated as $F_{VCO}/128$ assuming output duty cycle is 50%.

Device Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. Values are expressed in nanoseconds unless otherwise noted.

Table 40: Clock-Capable Clock Input to Output Delay Without MMCM/PLL (Near Clock Region)

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, <i>without</i> MMCM/PLL.							
T _{ICKOFF}	Clock-capable clock input and OUTFF <i>without</i> MMCM/PLL (near clock region)	XC7K70T	4.98	5.49	6.17	7.04	ns
		XC7K160T	5.23	5.77	6.48	7.38	ns
		XC7K325T	5.72	6.31	7.09	8.07	ns
		XC7K355T	5.34	5.87	6.57	7.51	ns
		XC7K410T	5.84	6.44	7.22	8.21	ns
		XC7K420T	5.50	6.04	6.77	7.73	ns
		XC7K480T	5.50	6.04	6.77	7.73	ns

Notes:

- Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.

Table 41: Clock-Capable Clock Input to Output Delay Without MMCM/PLL (Far Clock Region)

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, <i>without</i> MMCM/PLL.							
T _{ICKOFFAR}	Clock-capable clock input and OUTFF <i>without</i> MMCM/PLL (far clock region)	XC7K70T	5.29	5.83	6.55	7.47	ns
		XC7K160T	5.84	6.45	7.24	8.24	ns
		XC7K325T	6.33	6.99	7.84	8.92	ns
		XC7K355T	5.95	6.55	7.32	8.36	ns
		XC7K410T	6.45	7.12	7.97	9.07	ns
		XC7K420T	6.41	7.06	7.90	9.01	ns
		XC7K480T	6.41	7.06	7.90	9.01	ns

Notes:

- Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.

Table 47: Clock-Capable Clock Input Setup and Hold With PLL

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
Input Setup and Hold Time Relative to Clock-Capable Clock Input Signal for SSTL15 Standard. ⁽¹⁾							
T _{PSPLLCC} / T _{PHPLLCC}	No Delay clock-capable clock input and IFF ⁽²⁾ with PLL	XC7K70T	2.75/-0.32	3.04/-0.32	3.33/-0.32	2.42/-0.54	ns
		XC7K160T	2.85/-0.31	3.16/-0.31	3.46/-0.31	2.59/-0.56	ns
		XC7K325T	2.91/-0.27	3.24/-0.27	3.54/-0.27	2.80/-0.56	ns
		XC7K355T	2.79/-0.27	3.12/-0.27	3.40/-0.27	2.67/-0.52	ns
		XC7K410T	2.91/-0.27	3.24/-0.27	3.53/-0.27	2.78/-0.56	ns
		XC7K420T	2.83/-0.20	3.12/-0.20	3.41/-0.20	2.61/-0.50	ns
		XC7K480T	2.83/-0.20	3.12/-0.20	3.41/-0.20	2.61/-0.50	ns

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 48: Data Input Setup and Hold Times Relative to a Forwarded Clock Input Pin Using BUFIO

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Input Setup and Hold Time Relative to a Forwarded Clock Input Pin Using BUFIO for SSTL15 Standard.						
T _{PSCS} /T _{PHCS}	Setup/Hold of I/O clock for HR I/O banks	-0.36/1.36	-0.36/1.50	-0.36/1.70	-0.44/1.87	ns
	Setup/Hold of I/O clock for HP I/O banks	-0.34/1.39	-0.34/1.53	-0.34/1.73	-0.44/1.87	ns

Table 49: Sample Window

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
T _{SAMP}	Sampling Error at Receiver Pins ⁽¹⁾	0.51	0.56	0.61	0.56	ns
T _{SAMP_BUFIO}	Sampling Error at Receiver Pins using BUFIO ⁽²⁾	0.30	0.35	0.40	0.35	ns

Notes:

1. This parameter indicates the total sampling error of the Kintex-7 FPGAs DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the MMCM to capture the DDR input registers' edges of operation. These measurements include:
 - CLK0 MMCM jitter
 - MMCM accuracy (phase offset)
 - MMCM phase shift resolution
 These measurements do not include package or clock tree skew.
2. This parameter indicates the total sampling error of the Kintex-7 FPGAs DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the BUFIO clock network and IDELAY to capture the DDR input registers' edges of operation. These measurements do not include package or clock tree skew.

GTX Transceiver Specifications

GTX Transceiver DC Input and Output Levels

Table 51 summarizes the DC output specifications of the GTX transceivers in Kintex-7 FPGAs. Consult [UG476: 7 Series FPGAs GTX/GTH Transceiver User Guide](#) for further details.

Table 51: GTX Transceiver DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
DV _{PPOUT}	Differential peak-to-peak output voltage ⁽¹⁾	Transmitter output swing is set to maximum setting	–	–	1000	mV
V _{CMOUTDC}	DC common mode output voltage.	Equation based	$V_{MGTAVTT} - DV_{PPOUT}/4$			mV
R _{OUT}	Differential output resistance		–	100	–	Ω
T _{OSKEW}	Transmitter output pair (TXP and TXN) intra-pair skew		–	2	12	ps
DV _{PPIN}	Differential peak-to-peak input voltage (external AC coupled)	>10.3125 Gb/s	150	–	1250	mV
		6.6 Gb/s to 10.3125 Gb/s	150	–	1250	mV
		≤ 6.6 Gb/s	150	–	2000	mV
V _{IN}	Absolute input voltage	DC coupled V _{MGTAVTT} = 1.2V	–200	–	V _{MGTAVTT}	mV
V _{CMIN}	Common mode input voltage	DC coupled V _{MGTAVTT} = 1.2V	–	2/3 V _{MGTAVTT}	–	mV
R _{IN}	Differential input resistance		–	100	–	Ω
C _{EXT}	Recommended external AC coupling capacitor ⁽²⁾		–	100	–	nF

Notes:

1. The output swing and preemphasis levels are programmable using the attributes discussed in [UG476: 7 Series FPGAs GTX/GTH Transceiver User Guide](#) and can result in values lower than reported in this table.
2. Other values can be used as appropriate to conform to specific protocols and standards.

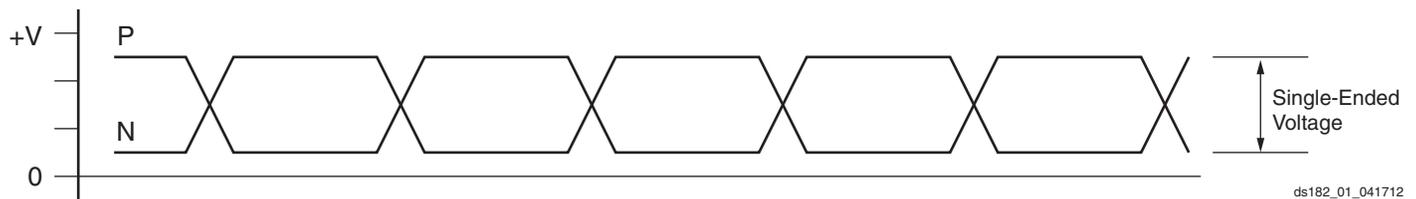


Figure 1: Single-Ended Peak-to-Peak Voltage

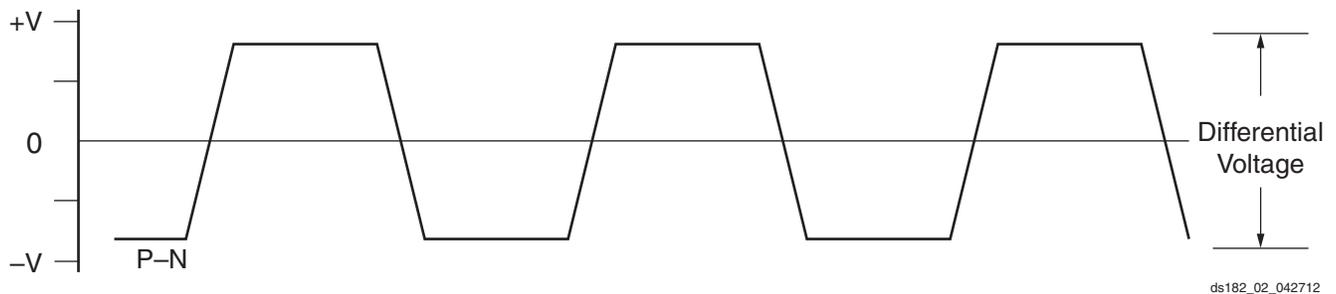


Figure 2: Differential Peak-to-Peak Voltage

Table 65: CPRI Protocol Characteristics

Description	Line Rate (Mb/s)	Min	Max	Units
CPRI Transmitter Jitter Generation				
Total transmitter jitter	614.4	–	0.35	UI
	1228.8	–	0.35	UI
	2457.6	–	0.35	UI
	3072.0	–	0.35	UI
	4915.2	–	0.3	UI
	6144.0	–	0.3	UI
	9830.4	–	Note 1	UI
CPRI Receiver Frequency Jitter Tolerance				
Total receiver jitter tolerance	614.4	0.65	–	UI
	1228.8	0.65	–	UI
	2457.6	0.65	–	UI
	3072.0	0.65	–	UI
	4915.2	0.95	–	UI
	6144.0	0.95	–	UI
	9830.4	Note 1	–	UI

Notes:

1. Tested per SFP+ specification, see Table 64.

Integrated Interface Block for PCI Express Designs Switching Characteristics

More information and documentation on solutions for PCI Express designs can be found at:

<http://www.xilinx.com/technology/protocols/pciexpress.htm>

Table 66: Maximum Performance for PCI Express Designs

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
F _{PIPECLK}	Pipe clock maximum frequency	250.00	250.00	250.00	250.00	MHz
F _{USERCLK}	User clock maximum frequency	500.00	500.00	250.00	250.00	MHz
F _{USERCLK2}	User clock 2 maximum frequency	250.00	250.00	250.00	250.00	MHz
F _{DRPCLK}	DRP clock maximum frequency	250.00	250.00	250.00	250.00	MHz

XADC Specifications

Table 67: XADC Specifications

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
$V_{CCADC} = 1.8V \pm 5\%$, $V_{REFP} = 1.25V$, $V_{REFN} = 0V$, $ADCCLK = 26\text{ MHz}$, $T_j = -40^\circ\text{C}$ to 100°C , Typical values at $T_j = +40^\circ\text{C}$						
ADC Accuracy⁽¹⁾						
Resolution			12	–	–	Bits
Integral Nonlinearity ⁽²⁾	INL		–	–	± 3	LSBs
Differential Nonlinearity	DNL	No missing codes, guaranteed monotonic	–	–	± 1	LSBs
Offset Error		Offset calibration enabled	–	–	± 6	LSBs
Gain Error		Gain calibration disabled	–	–	± 0.5	%
Offset Matching		Offset calibration enabled	–	–	4	LSBs
Gain Matching		Gain calibration disabled	–	–	0.3	%
Sample Rate			0.1	–	1	MS/s
Signal to Noise Ratio ⁽²⁾	SNR	$F_{SAMPLE} = 500\text{KS/s}$, $F_{IN} = 20\text{KHz}$	60	–	–	dB
RMS Code Noise		External 1.25V reference	–	–	2	LSBs
		On-chip reference	–	3	–	LSBs
Total Harmonic Distortion ⁽²⁾	THD	$F_{SAMPLE} = 500\text{KS/s}$, $F_{IN} = 20\text{KHz}$	–	70	–	dB
ADC Accuracy at Extended Temperatures (-55°C to 125°C)						
Resolution			10	–	–	Bits
Integral Nonlinearity ⁽²⁾	INL		–	–	± 1	LSB (at 10 bits)
Differential Nonlinearity	DNL	No missing codes, guaranteed monotonic	–	–	± 1	
Analog Inputs⁽³⁾						
ADC Input Ranges		Unipolar operation	0	–	1	V
		Bipolar operation	-0.5	–	+0.5	V
		Unipolar common mode range (FS input)	0	–	+0.5	V
		Bipolar common mode range (FS input)	+0.5	–	+0.6	V
Maximum External Channel Input Ranges		Adjacent channels set within these ranges should not corrupt measurements on adjacent channels	-0.1	–	V_{CCADC}	V
Auxiliary Channel Full Resolution Bandwidth	FRBW		250	–	–	KHz
On-Chip Sensors						
Temperature Sensor Error		$T_j = -40^\circ\text{C}$ to 100°C .	–	–	± 4	$^\circ\text{C}$
		$T_j = -55^\circ\text{C}$ to $+125^\circ\text{C}$	–	–	± 6	$^\circ\text{C}$
Supply Sensor Error		Measurement range of $V_{CCAUX} 1.8V \pm 5\%$ $T_j = -40^\circ\text{C}$ to $+100^\circ\text{C}$	–	–	± 1	%
		Measurement range of $V_{CCAUX} 1.8V \pm 5\%$ $T_j = -55^\circ\text{C}$ to $+125^\circ\text{C}$	–	–	± 2	%
Conversion Rate⁽⁴⁾						
Conversion Time - Continuous	t_{CONV}	Number of ADCCLK cycles	26	–	32	Cycles
Conversion Time - Event	t_{CONV}	Number of CLK cycles	–	–	21	Cycles
DRP Clock Frequency	DCLK	DRP clock frequency	8	–	250	MHz
ADC Clock Frequency	ADCCLK	Derived from DCLK	1	–	26	MHz
DCLK Duty Cycle			40	–	60	%

Revision History

The following table shows the revision history for this document:

Date	Version	Description
03/01/11	1.0	Initial Xilinx release.
04/01/11	1.1	Added the XC7K355T, XC7K420T, and XC7K480T devices throughout data sheet. Added the extended temperature range discussion to page 1 . Updated V_{CCAUX_IO} in Table 2 . Edits to clarify Power-On/Off Power Supply Sequencing power sequencing discussion. Added I_{CCAUX_IO} and I_{CCBRAM} to Table 6 and Table 7 . Updated $MMCM_FINDUTY$ and added $F_{INJITTER}$, $T_{OUTJITTER}$, $T_{EXTFVAR}$, and Note 3 to Table 38 . Removed the SBG324 package from Table 50 . Updated the Notice of Disclaimer .
10/04/11	1.2	Replaced -1L with -2L throughout this data sheet. Updated Min/Max values and removed Note 5 from Table 2 . Clarified Power-On/Off Power Supply Sequencing power sequencing discussion including adding $T_{VCCO2VCCAUX}$ to Table 8 . Updated V_{ICM} in Table 12 and Table 13 . Added Note 1 to table 12 . Updated Table 69 including adding Note 1 . Added <i>Absolute Maximum Ratings for GTX Transceivers</i> . Revised the reference clock maximum frequency (F_{GCLK}) in Table 55 . Added Table 57 . Added LVTTTL and removed SSTL135_II and SSTL15_II specifications from Table 19 . Removed HSTL_III from Table 20 . Removed the <i>I/O Standard Adjustment Measurement Methodology</i> section. Use IBIS for more accurate information and measurements. Updated $T_{DELAYPAT_JIT}$ in Table 26 . Added T_{AS}/T_{AH} to Table 28 . Added $T_{RDCK_DI_WF_NC}/T_{RCKD_DI_WF_NC}$ and $T_{RDCK_DI_RF}/T_{RCKD_DI_RF}$ to Table 31 . Completely updated Table 68 . Updated the AC Switching Characteristics in Table 19 , Table 20 , Table 21 , Table 22 , Table 23 , Table 24 , Table 26 through Table 38 , Table 40 through Table 37 , and Table 67 .
11/03/11	1.3	Revised the V_{OCM} specification in Table 12 . Updated the AC Switching Characteristics based upon the ISE 13.3 v1.02 speed specification throughout document including Table 19 and Table 20 . Added $MMCM_T_{FBDELAY}$ while adding $MMCM_$ to the symbol names of a few specifications in Table 38 and PLL to the symbol names in Table 39 . In Table 40 through Table 47 , updated the pin-to-pin descriptions with the SSTL15 standard. Updated units in Table 49 .
02/13/12	1.4	Updated summary description on page 1 . In Table 2 , revised V_{CCO} for the 3.3V HR I/O banks and updated T_j . Added typical values to Table 3 . Updated the notes in Table 6 . Added MGTAVCC, MGTAVTT, and MGTVCCAUX power supply ramp times to Table 8 . Rearranged Table 9 , added Mobile_DDR, HSTL_I_18, HSTL_II_18, HSUL_12, SSTL135_R, SSTL15_R, and SSTL12 and removed DIFF_SSTL135, DIFF_SSTL18_I, DIFF_SSTL18_II, DIFF_HSTL_I, and DIFF_HSTL_II. Added Table 10 and Table 11 . Revised the specifications in Table 12 and Table 13 . Updated the eFUSE Programming Conditions section and removed the endurance table. Added the IO_FIFO Switching Characteristics table. Revised I_{CCADC} and updated Note 1 in Table 67 . Revised DDR LVDS transmitter data width in Table 16 . Updated the AC Switching Characteristics based upon the ISE 13.4 v1.03 speed specification throughout document. Removed notes from Table 28 as they are no longer applicable. Updated specifications in Table 68 . Updated Note 1 in Table 37 . In the GTX Transceiver DC Input and Output Levels section: Revised V_{IN} , and added I_{DCIN} and I_{DCOUT} to Table 51 . Added Note 4 to Table 53 . In Table 55 , revised F_{GCLK} , removed T_{PHASE} , and added T_{DLOCK} . Revised specifications and added Note 2 to Table 57 . Added Table 58 and Table 59 along with GTX Transceiver Protocol Jitter Characteristics in Table 60 through Table 65 .
05/23/12	1.5	Reorganized entire data sheet including adding Table 44 and Table 48 . Updated T_{SOL} in Table 1 . Updated I_{BATT} and added R_{IN_TERM} to Table 3 . Added values to Table 6 and Table 7 . Updated Power-On/Off Power Supply Sequencing , page 6 with regards to GTX transceivers. Updated many parameters in Table 9 including SSTL135 and SSTL135_R. Removed V_{OX} column and added DIFF_HSUL_12 to Table 11 . Updated V_{OL} in Table 12 . Updated Table 16 and removed notes 2 and 3. Updated Table 17 . Updated the AC Switching Characteristics based upon the ISE 14.1 v1.04 for the -3, -2, -2L (1.0V), -1, and -2L (0.9V) speed specifications throughout the document. In Table 31 , updated Reset Delays section including Note 10 and Note 11 . Added data for T_{LOCK} and T_{DLOCK} in Table 55 . Updated many of the XADC specifications in Table 67 and added Note 2 . Updated and moved <i>Dynamic Reconfiguration Port (DRP) for MMCM Before and After DCLK</i> section from Table 68 to Table 38 and Table 39 .